

Title (en)

METHOD FOR EXAMINING A MEASUREMENT OBJECT, AND APPARATUS

Title (de)

VERFAHREN ZUM UNTERSUCHEN EINES MESSOBJEKTES UND VORRICHTUNG

Title (fr)

PROCEDE D'ANALYSE D'UN OBJET A MESURER, ET DISPOSITIF CORRESPONDANT

Publication

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Application

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Abstract (en)

[origin: WO2007041976A1] The invention relates to a method for examining a measurement object (2, 12), in which the measurement object (2, 12) is examined by means of scanning probe microscopy using a measurement probe (10) of a scanning probe measurement device and in which at least one subsection (1) of the measurement object (2, 12) is optically examined, in an observation region associated with an optical measurement system, using the optical measurement system, wherein displacement of the at least one subsection (1) of the measurement object (2, 12) from the observation region, said displacement being caused by the examination by means of scanning probe microscopy, is corrected in such a manner that the at least one displaced subsection (1) of the measurement object (2, 12) is arranged in the observation region again with the aid of an adjusting device which processes data signals which characterize the displacement.

IPC 8 full level

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